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Giancarlo Pepponi currently coordinates the Materials Characterization area (MateC) of the Micro-Nano fabrication and characterization Facility (MNF) of the Centre for Materials and Microsystems, Fondazione Bruno Kessler, Trento Italy. After having graduated in Physics at the University of Trento (1999) he earned a PhD in technical physics at the Vienna University of Technology(2003) defending a thesis with title “Synchrotron Radiation induced Total Reflection X-Ray Fluorescence Analysis applied to Material Science”. He is author and co-author of over 75 articles in refereed journals mostly related to X-Ray Spectrometry for elemental analysis and materials characterisation where his contributions involved both the experimental and the computational (data evaluation) activities. Recent research interests involve the combination of analytical techniques (e.g. combined XRF and XRD analysis) as well as the design and testing of semiconductor detectors for specific analytical needs and applications.